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Experiments with Multiply-Charged Lanthanide Ions in the NIST EBIT

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Primary authors: TAN, Joseph (National Institute of Standards and Technology); NAING, Aung Sis (University of Delaware / NIST); Dr NORRGARD, Eric (National Institute of Standards & Technology); SMALL, Angela (University of Maryland at College Park); SANDERS, Samuel (Clemson University); SILWAL, Roshani (Clemson University); TAKACS, Endre (Clemson University / NIST); RALCHENKO, Yuri (National Institute of Standards & Technology)

Presenter: TAN, Joseph (National Institute of Standards and Technology)